Form PTO 1449 (Modified)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO.		SERIAL NO.				
				246703US2S	New Application					
LIST OF	DEEE	RENCES CITED BY AP	IDI ICANIT	APPLICANT						
LISTOF	REFER	RENCES CITED BY AF	PEICANT	Takeshi KAJIYAMA						
				FILING DATE	GROUP					
				Herewith						
				U.S. PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS			LING DATE PPROPRIATE		
1119	- AA	6,590,244	07/08/2003	Yoshiaki ASAO, et al.						
	AB									
	AC		1.							
	AD									
	AE		<u> </u>		<u> </u>					
	AF		<u> </u>		<u> </u>		_			
<u> </u>	AG				<u> </u>					
<u> </u>	AH		· · · · · · · · · · · · · · · · · · ·							
ļ	Al		<del>                                     </del>							
<u> </u>	·	<del></del>	<del> </del>							
	AJ		<u> </u>	•	<del> </del>					
	AK		<u> </u>		ļ			<u>'</u>		
	AL	-	<u> </u>					· · · · · · · · · · · · · · · · · · ·		
	AM		<del> </del>		ļ					
	AN			`	<u> </u>					
			FO	REIGN PATENT DOCUMENTS						
		DOCUMENT	DATE	COUNTRY		TRANSLATION		LATION		
11		NUMBER				YES	3	NO		
100	AO	2002-289807	10/04/2002	JAPAN				· X		
1/1/	AP	2001-519092	10/16/2001	JAPAN				X		
119	AQ	2002-110938	04/12/2002	JAPAN				X		
	AR									
	AS		<u> </u>							
	AT	•								
	AU		ļ	·						
	AV		·			<u> </u>				
	•	OTHER RI	EFERENCES (	Including Author, Title, Date, Pertinen	t Pages, e	tc.)				
	AW									
	AX									
	~									
	AY									
	AZ	1//		Additional References sheet(s) attached						
Examiner Date Cons							insidered D \$\D 4/07			
*Examiner /hitial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.										

			Kee	8						
Form PTO 1449		U.S. DEPARTMENT PATENT AND TRAD	FROMMERCE EMERICOSFICE	ANY DOCKET NO.	SERIAL N					
(Modified)		PAICNI AND IRAD	THE STAN		10/736,	<b>03</b> 1				
			NICANT	APPLICANT						
LIST OF	REFERE	NCES CITED BY API	PLICANI	Takeshi KAJIYAMA						
				FILING DATE	GROUP					
-				December 17, 2003		L	<del></del>			
				U.S. PATENT DOCUMENTS	·	·	<del> </del>			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS			ING DATE PROPRIATE		
-	AA									
	AB				4					
٥	AC				<u> </u>					
	AD					ļ				
	AE		<u></u>			<u> </u>	ļ.——			
	AF				ļ	ļ				
	AG				<u> </u>	<u> </u>				
	АН			·	ļ <u> </u>	<u> </u>	<u> </u>			
	Al				<b>_</b>	<del> </del>				
	AJ					<b></b>	<u> </u>			
	AK					ļ	ļ			
	AL				<u> </u>	<b> </b>				
	AM					ļ	ļ			
•	AN				<u> </u>	<u> </u>	<u> </u>			
	<u> </u>		F	OREIGN PATENT DOCUMENTS						
	Т	DOCUMENT DATE COUNTRY				TRANSLATION				
		NUMBER	DATE	COUNTRY			S	NO		
	AO					<u> </u>				
	AP					<u> </u>				
	AQ		·							
	AR					<u> </u>				
	AS	,			<u> </u>					
	AT									
	AU									
	AV									
<u> </u>		OTHER I	REFERENCES	S (Including Author, Title, Date, Pertine	ent Pages,	etc.)				
1-1	т			O COOR Technical Digget 2000 IEEE Inte	mational S	Solid-State	Circuits C	Conference,		
16/1	AW	Lunt 42 magas 128-1	20 °A 10NS F	C 2000 Technical Digest, 2000 IEEE THE READ AND WRITE NON-VOLATILE MEI EACH CELL", February 7, 8, and 9, 200	4101X 1 701XI	RAY USING		NETIC TUNNEL		
,	AX									
	AY	·						<u>:</u>		
	AZ)	Additional Refer						s sheet(s) attache		
Examiner	1//	han-	1/12		Date (	Considered	6 f	104/0		
45	nitial if	reference is considere	ed, whether or	not citation is in conformance with MPEF orm with next communication to applican	- 609; Drav	w line throu	igh citation	in if not in		
conforman	ce and n	ot considered. Include	copy of tris i	OHIT WILL HOAT COMMISSION CONTROL						